

MOSFET

600V CoolMOS™ CM8 Power Transistor

Built on Infineon's world-class super-junction MOSFET platform with an integrated fast body diode, making it suitable for a wide range of applications. It enables highest power density at lowest possible system cost with superior reliability. It is enhancing Infineon's WBG offering and the successor of the 600 V CoolMOS™ 7 MOSFET family.

Drain

Pin 12-22. Tab

Source

Pin 3-11

Gate Pin 1

Drive

Source

Pin 2

*1: Internal body diode

O-DPAK

Features

- Best-In-Class SJ Mosfet Performance
- Address broad hard and soft switching applications with outstanding commutation ruggedness
- Integrated fast body diode and ESD protection
- .XT interconnection technology for best-in-class thermal performance

Benefits

- Provides the best price performance ratio with Best-In-Class SJ Mosfet Performance
- Ease of use and shorter design in cycle
- Enable multiple topologies
- 14-42% lower R_{th} for improved thermal performance

Potential applications

- Datacenter, Al server, Telecom Power Supply
- Micro and Residential Hybrid Inverter
- Portable and Residential Energy Storage, UPS
- EV Charging, Light electric vehicles, Electric Forklift
- High Voltage Solid State Power Distribution
- Home & Professional Tools

Product validation

Fully qualified according to JEDEC for Industrial Applications

Please note: For MOSFET paralleling the use of ferrite beads on the gate or separate totem poles is generally recommended.

Table 1 Key performance parameters

Parameter	Value	Unit
V _{DS} @ T _{j,max}	650	V
$R_{DS(on),max}$	70	mΩ
$Q_{g,typ}$	43	nC
I _{D,pulse}	124	A
E _{oss} @ 400V	5.9	μЈ
Body diode di _F /dt	1300	A/μs
ESD class (HBM)	2	

Type / Ordering code	Package	Marking	Related links
IPDQ60R070CM8	PG-HDSOP-22	60R070C8	see Appendix A



Public

600V CoolMOS™ CM8 Power Transistor IPDQ60R070CM8



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1 Maximum ratings at $T_j = 25$ °C, unless otherwise specified

Maximum ratings Table 2

Davamatav	Cumphal		Values		115:4	Note / Test condition	
Parameter	Symbol	Min.	Тур.	Max.	Jonic	Note / Test condition	
Continuous drain current ¹⁾	I _D	-	-	37	А	T _c =25°C	
Continuous drain current	I _D	-	-	23	А	T _C =100°C	
Pulsed drain current ²⁾	I _{D,pulse}	-	-	124	А	T _c =25°C	
Avalanche energy, single pulse	E _{AS}	-	-	73	mJ	1 -2 FA-V - FOVe see table 10	
Avalanche energy, repetitive	E _{AR}	-	-	0.36	mJ	I _D =3.5A; V _{DD} =50V; see table 10	
Avalanche current, single pulse	I _{AS}	-	-	3.5	А	-	
MOSFET dv/dt ruggedness	dv/dt	-	-	120	V/ns	V _{DS} =0400V	
Gate source voltage (static)	$V_{\rm GS}$	-20	-	20	V	static;	
Gate source voltage (dynamic)	$V_{\rm GS}$	-30	-	30	V	AC (f>1 Hz)	
Power dissipation	P _{tot}	-	-	205	W	T _C =25°C	
Storage temperature	$T_{\rm stg}$	-55	-	150	°C		
Operating junction temperature	$T_{\rm j}$	-55	-	150	°C		
Extended operating junction temperature	$T_{\rm j}$	150	-	175	°C	≤50 h in the application lifetime	
Mounting torque	-	-	-	-	Ncm	-	
Continuous diode forward current	I _S	-	-	37	Α	T 250C	
Diode pulse current ²⁾	I _{S,pulse}	-	-	124	А	<i>T</i> _C =25°C	
Reverse diode dv/dt ³⁾	dv/dt	-	-	70	V/ns	<i>V</i> _{DS} =0400V, <i>I</i> _{SD} ≤37A, <i>T</i> _j =25°C see table 8	
Maximum diode commutation speed	di _F /dt	-	-	1300	A/μs		
Insulation withstand voltage	V _{ISO}	-	-	n.a.	V	V _{rms} , T _C =25°C, <i>t</i> =1min	

Limited by $T_{j,max}$.

²⁾ Pulse width t_p limited by T_{j,max}

 $^{^{\}rm 3)}$ $\,$ Identical low side and high side switch with identical $\rm R_{\rm G}$



2 Thermal characteristics

Table 3 Thermal characteristics

Darameter	Symbol	Values			l lmit	Note / Test condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test condition
Thermal resistance, junction - case	$R_{\rm thJC}$	-	-	0.61	K/W	-
Thermal resistance, junction - ambient	R_{thJA}	-	-	62	K/W	device on PCB, minimal footprint
Thermal resistance, junction - ambient for SMD version	R_{thJA}	-	-	-	K/W	-
Soldering temperature, reflow soldering allowed	T_{sold}	-	-	260	°C	reflow MSL1



3 Electrical characteristics

at T_i =25°C, unless otherwise specified

Table 4 Static characteristics

Davamatav	Cymphal	Values			1154	Note / Test son dition	
Parameter	Symbol	Min.	Тур.	Max.	Onic	Note / Test condition	
Drain-source breakdown voltage	$V_{(BR)DSS}$	600	-	-	V	$V_{\rm GS}$ =0V, $I_{\rm D}$ =1mA	
Gate threshold voltage	$V_{(GS)th}$	3.7	4.2	4.7	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 0.36 \rm mA$	
Zero gate voltage drain current	I _{DSS}	-	- 45.1	1	μΑ	$V_{\rm DS}$ =600V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C $V_{\rm DS}$ =600V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =150°C	
Gate-source leakage current	I _{GSS}	-	-	0.1	μΑ	V _{GS} =20V, V _{DS} =0V	
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	-	0.058 0.127	0.070 -	Ω	V_{GS} =10V, I_D =14.3A, T_j =25°C V_{GS} =10V, I_D =14.3A, T_j =150°C	
Gate resistance	R_{G}	-	5.6	-	Ω	<i>f</i> =1MHz	

Table 5 Dynamic characteristics

Parameter	Cymphol	Values			l lait	Note / Took oo w dition	
	Symbol	Min.	Тур.	Max.	Onit	Note / Test condition	
Input capacitance	C _{iss}	-	1878	-	pF	1/ -0/ 1/ -400// [250]/ -	
Output capacitance	C _{oss}	-	25	-	pF	V _{GS} =0V, V _{DS} =400V, <i>f</i> =250kHz	
Effective output capacitance, energy related ⁴⁾	$C_{\rm o(er)}$	-	73	-	pF	V _{GS} =0V, V _{DS} =0400V	
Effective output capacitance, time related ⁵⁾	$C_{\rm o(tr)}$	-	749	-	pF	$I_{\rm D}$ =constant, $V_{\rm GS}$ =0V, $V_{\rm DS}$ =0400V	
Turn-on delay time	$t_{\sf d(on)}$	-	17.8	-	ns		
Rise time	t _r	-	6.2	-	ns	$V_{\rm DD}$ =400V, $V_{\rm GS}$ =13V, $I_{\rm D}$ =7.3A, $R_{\rm G}$ =5.3 Ω ; see table 9	
Turn-off delay time	$t_{ m d(off)}$	-	94.9	-	ns		
Fall time	t _f	-	8	-	ns		

⁴⁾ $C_{
m o(er)}$ is a fixed capacitance that gives the same stored energy as $C_{
m oss}$ while $V_{
m DS}$ is rising from 0 to 400V

⁵⁾ $C_{\text{o(tr)}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400V



Table 6 Gate charge characteristics

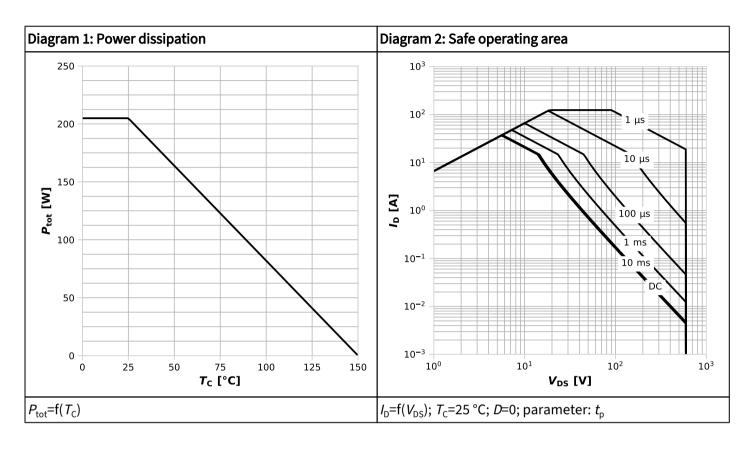
Parameter	Symbol	Values			Linit	Note / Test condition
Parameter	Syllibol	Min.	Тур.	Max.	Onit	Note / Test condition
Gate to source charge	Q_{gs}	-	11	-	nC	
Gate to drain charge	Q_{gd}	-	16	-	nC	$V_{\rm DD}$ =400V, $I_{\rm D}$ =7.3A, $V_{\rm GS}$ =0 to 10V
Gate charge total	$Q_{ m g}$	-	43	-	nC	
Gate plateau voltage	$V_{ m plateau}$	-	6.0	-	V	

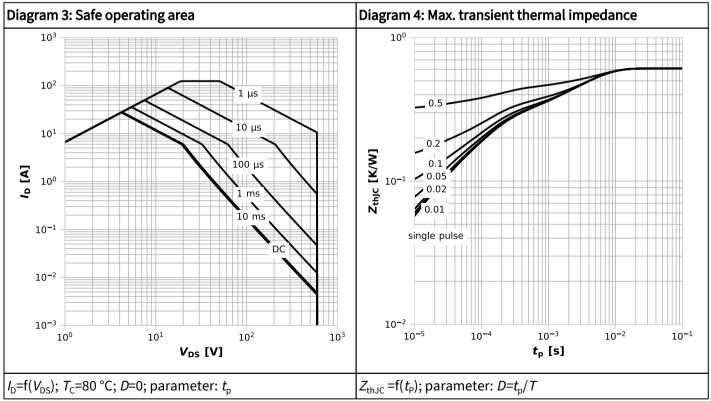
Table 7 Reverse diode characteristics

Parameter	Symbol	Values			Linit	Note / Test condition	
raiailletei	Symbol	Min.	Тур.	Max.	Onic	Note / Test condition	
Diode forward voltage	$V_{\rm SD}$	-	0.9	-	V	$V_{\rm GS}$ =0V, $I_{\rm F}$ =7.3A, $T_{\rm j}$ =25°C	
Reverse recovery time	t _{rr}	-	90.14	112.68	ns		
Reverse recovery charge	$Q_{\rm rr}$	-	0.41	0.61	111($V_{\rm R}$ =400V, $I_{\rm F}$ =7.3A, d $i_{\rm F}$ /d t =100A/ μ s; see table 8	
Peak reverse recovery current	I _{rrm}	-	9.34	-	Α		

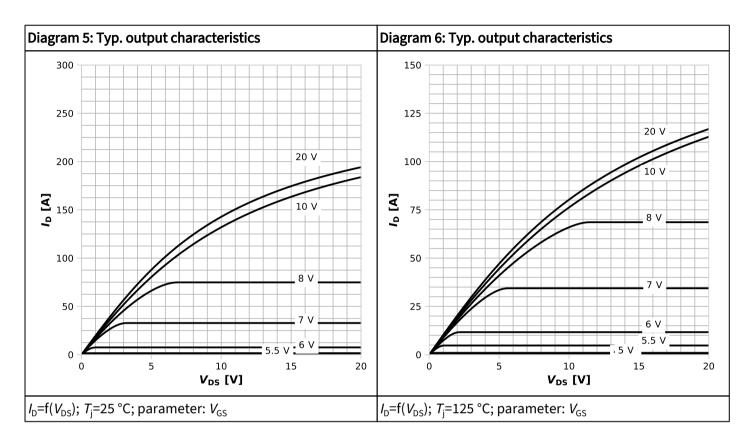


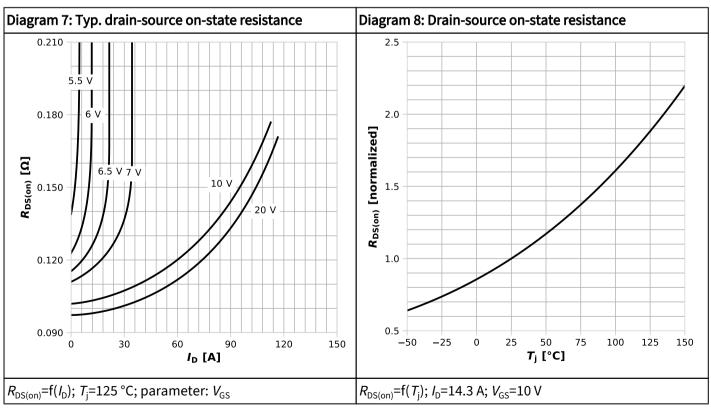
4 Electrical characteristics diagrams



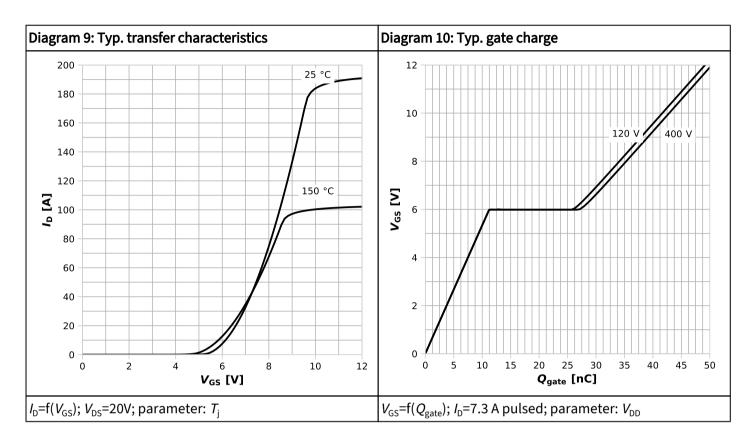


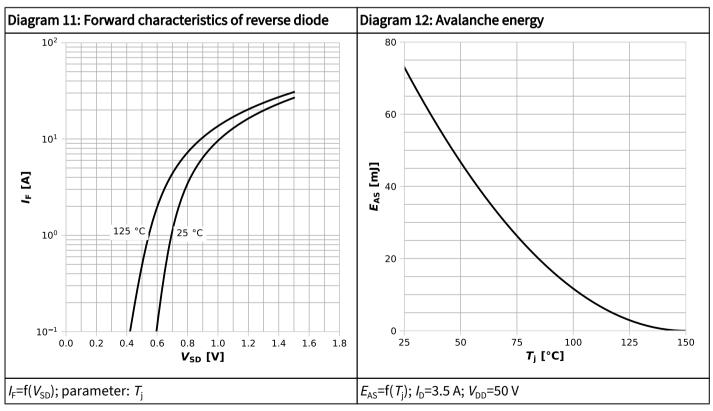




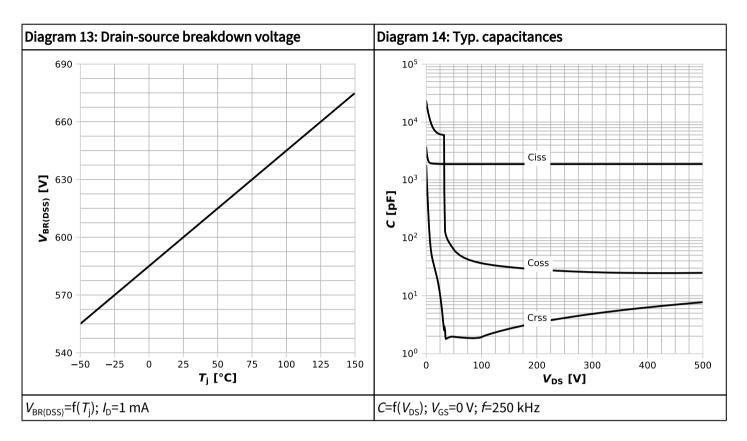


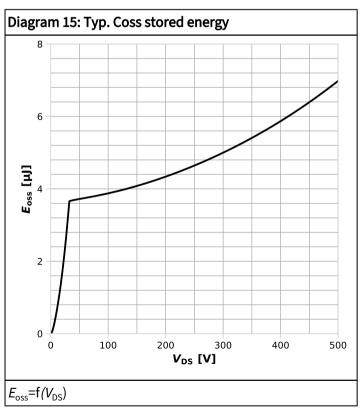














5 Test circuits

Table 8 Diode characteristics

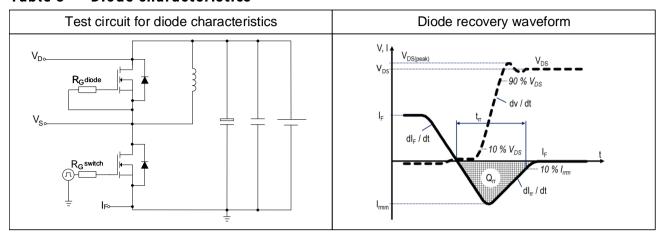


Table 9 Switching times

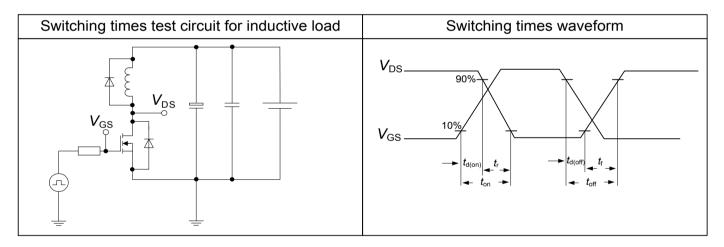
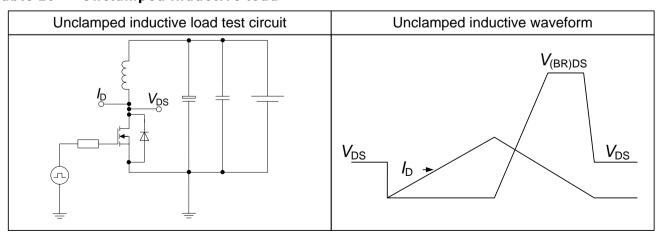


Table 10 Unclamped inductive load





6 Package outlines

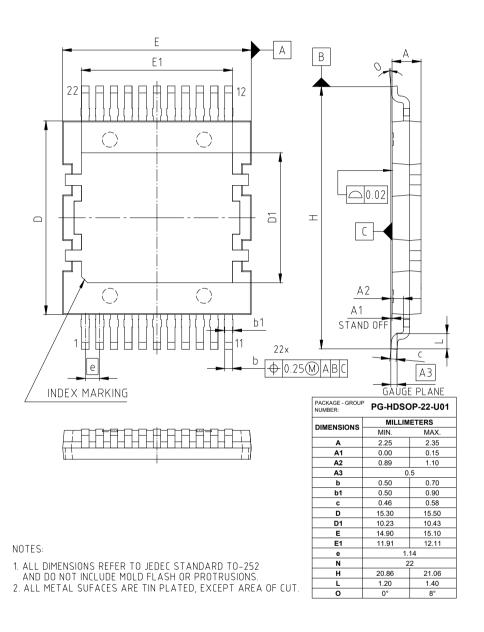


Figure 1 Outline PG-HDSOP-22, dimensions in mm



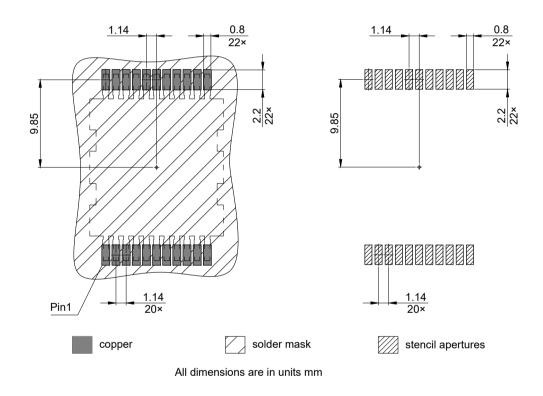


Figure 2 Footprint drawing PG-HDSOP-22, dimensions in mm



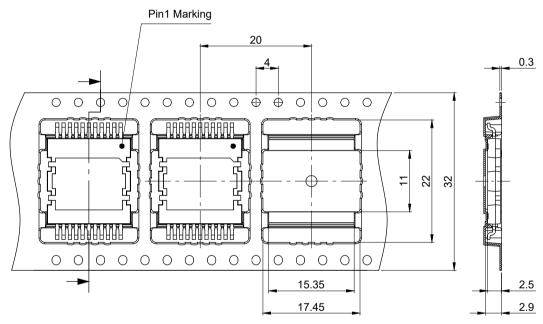


Figure 3 Packaging variant PG-HDSOP-22, dimensions in mm



7 Appendix A

Table 11 Related links

- IFX CoolMOS CM8 Webpage
- IFX CoolMOS CM8 application note
- IFX CoolMOS CM8 simulation model
- IFX Design tools



Revision history

IPDO60R070CM8

Revision 2024-12-18, Rev. 2.0

Previous revisions

Revision	sion Date Subjects (major changes since last revision)				
2.0	2024-12-18	Release of final version			

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